

FEATURES

- On-Chip Latches for Both DACs
- +5 V to +15 V Operation
- DACs Matched to 1%
- Four Quadrant Multiplication
- 15 V CMOS Compatible
- See MP7529A or MP7529B for Improved Performance

APPLICATIONS

- Microprocessor Controlled Gain Circuits
- Microprocessor Controlled Attenuator Circuits
- Microprocessor Controlled Function Generation
- Precision AGC Circuits
- Bus Structured Instruments

GENERAL DESCRIPTION

The MP7528 is a dual 8-bit digital/analog converter designed using EXAR's proven decoded DAC architecture. It features excellent DAC-to-DAC matching and guaranteed monotonicity.

Separate on-chip latches are provided for each DAC to allow easy microprocessor interface.

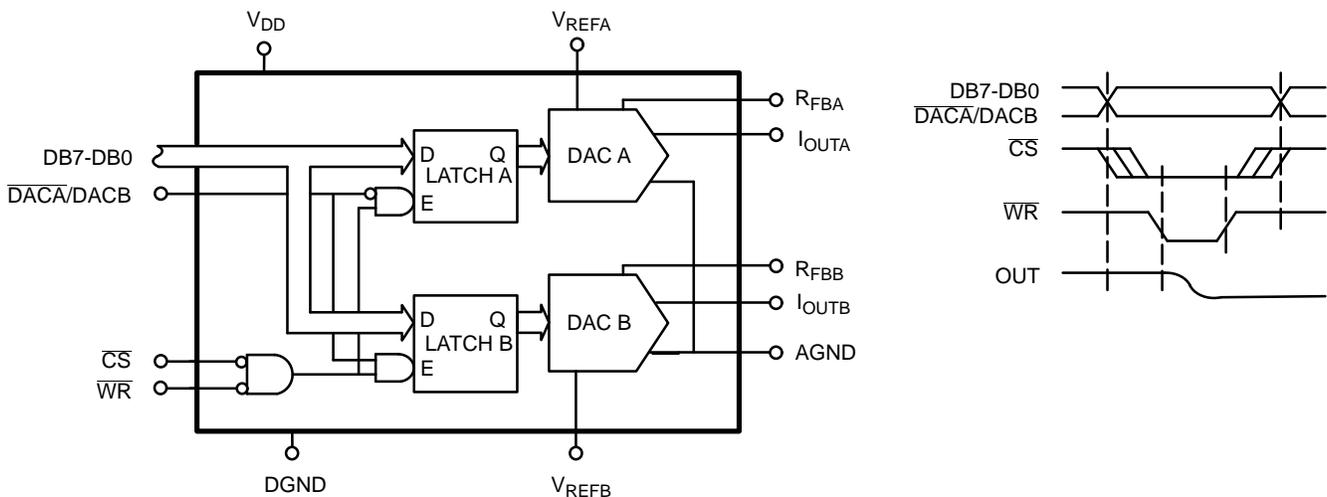
Data is transferred into either of the two DAC data latches via a common 8-bit TTL/CMOS compatible input port. Control input

$\overline{DACA}/\overline{DACB}$ determines which DAC is to be loaded. The MP7528's load cycle is similar to the write cycle of a random access memory and the device is bus compatible with most 8-bit microprocessors.

The device operates from a +5V to +15V power supply with only 2 mA of current (maximum).

Both DACs offer excellent four quadrant multiplication characteristics with a separate reference input and feedback resistor for each DAC.

SIMPLIFIED BLOCK AND TIMING DIAGRAM



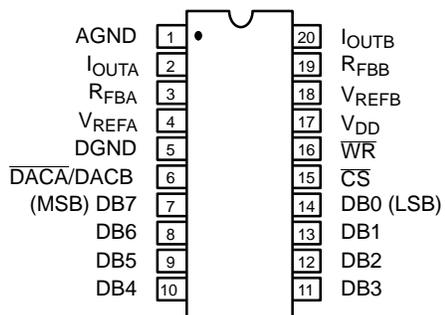
ORDERING INFORMATION

| Package Type | Temperature Range | Part No. | INL (LSB) | DNL (LSB) | Gain Error (LSB) |
|--------------|-------------------|-----------|-----------|-----------|------------------|
| Plastic Dip | -40 to +85°C | MP7528JN | ±1 | ±1 | ±6 |
| Plastic Dip | -40 to +85°C | MP7528KN | ±1/2 | ±1 | ±4 |
| Plastic Dip | -40 to +85°C | MP7528LN | ±1/4 | ±1 | ±3 |
| SOIC | -40 to +85°C | MP7528JS | ±1 | ±1 | ±6 |
| SOIC | -40 to +85°C | MP7528KS | ±1/2 | ±1 | ±4 |
| SOIC | -40 to +85°C | MP7528LS | ±1/4 | ±1 | ±3 |
| PLCC | -40 to +85°C | MP7528JP | ±1 | ±1 | ±6 |
| PLCC | -40 to +85°C | MP7528KP | ±1/2 | ±1 | ±4 |
| PLCC | -40 to +85°C | MP7528LP | ±1/4 | ±1 | ±3 |
| Ceramic Dip | -40 to +85°C | MP7528AD | ±1 | ±1 | ±6 |
| Ceramic Dip | -40 to +85°C | MP7528BD | ±1/2 | ±1 | ±4 |
| Ceramic Dip | -40 to +85°C | MP7528CD | ±1/4 | ±1 | ±3 |
| Ceramic Dip | -55 to +125°C | MP7528SD* | ±1 | ±1 | ±6 |
| Ceramic Dip | -55 to +125°C | MP7528TD* | ±1/2 | ±1 | ±4 |

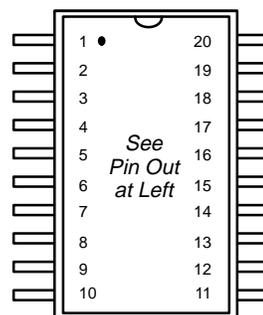
*Contact factory for non-compliant military processing

PIN CONFIGURATIONS

See Packaging Section for Package Dimensions

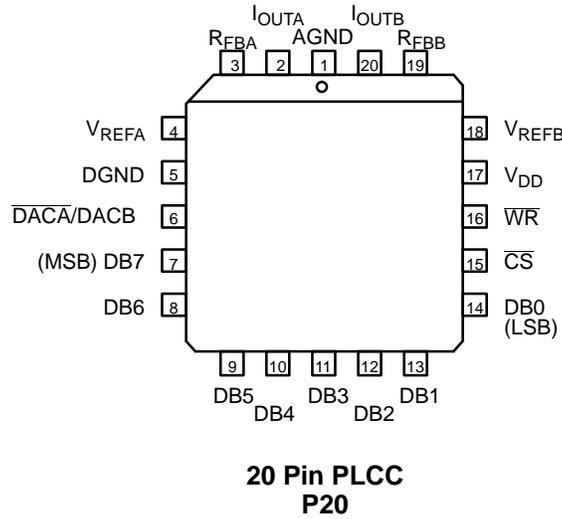


20 Pin CDIP, PDIP (0.300")
D20, N20



20 Pin SOIC (Jedec, 0.300")
S20

PIN CONFIGURATIONS (CONT'D)



PIN OUT DEFINITIONS

| PIN NO. | NAME | DESCRIPTION |
|---------|-----------------|-----------------------------|
| 1 | AGND | Analog Ground |
| 2 | IOUTA | Current Out DAC A |
| 3 | RFBA | Feedback Resistor for DAC A |
| 4 | VREFA | Reference Input for DAC A |
| 5 | DGND | Digital Ground |
| 6 | DAC A/ DAC B | DAC Select |
| 7 | DB7 (MSB) | Data Input Bit 7 |
| 8 | DB6 | Data Input Bit 6 |
| 9 | DB5 | Data Input Bit 5 |
| 10 | DB4 | Data Input Bit 4 |
| 11 | DB3 | Data Input Bit 3 |
| 12 | DB2 | Data Input Bit 2 |
| 13 | DB1 | Data Input Bit 1 |
| 14 | DB0 (LSB) | Data Input Bit 0 |
| 15 | CS | Chip Select |
| 16 | WR | Write |
| 17 | VDD | Power Supply |
| 18 | VREFB | Reference Input for DAC B |
| 19 | RFBB | Feedback Resistor for DAC B |
| 20 | IOUTB | Current Out DAC B |

ELECTRICAL CHARACTERISTICS (VDD = + 5 V, VREF = +10 V unless otherwise noted)

| Parameter | Symbol | 25°C | | | Tmin to Tmax | | Units | Test Conditions/Comments |
|---|-------------------|------|-----|-------|--------------|-----|--------|---|
| | | Min | Typ | Max | Min | Max | | |
| STATIC PERFORMANCE¹ | | | | | | | | |
| Resolution (All Grades) | N | 8 | | | 8 | | | Bits |
| Integral Non-Linearity (Relative Accuracy) | INL | | | | | | LSB | End Point Linearity Spec. |
| J, A, S | | | | ±1 | | | ±1 | |
| K, B, T | | | | ±1/2 | | | ±1/2 | |
| L, C | | | | ±1/4 | | | ±1/4 | |
| Monotonicity | | | | | | | | Guaranteed over temp |
| Differential Non-Linearity | DNL | | | ±1 | | | ±1 | LSB |
| J, A, S | | | | | | | | |
| K, B, T | | | | | | | | |
| L, C | | | | | | | | |
| Gain Error | GE | | | | | | | LSB |
| J, A, S | | | | ±4 | | | ±6 | |
| K, B, T | | | | ±2 | | | ±4 | |
| L, C | | | | ±1 | | | ±3 | |
| Gain Temperature Coefficient ² | TC _{GE} | | | | | | ±70 | ppm/°C |
| Power Supply Rejection Ratio | PSRR | | | ±200 | | | ±400 | ppm/% |
| Output Leakage Current (Pin 2) | I _{OUT1} | | | ±50nA | | | ±400nA | nA |
| Output Leakage Current (Pin 20) | I _{OUT2} | | | ±50nA | | | ±400nA | nA |
| Input Resistance | V _{REFA} | 8 | | 15 | 8 | 15 | | kΩ |
| | V _{REFB} | 8 | | 15 | 8 | 15 | | kΩ |
| Input Resistance Matching | | | | ±1 | | | ±1 | % |
| DYNAMIC PERFORMANCE² | | | | | | | | |
| Harmonic Distortion | THD | | | -85 | | | | dB |
| Digital Crosstalk | Q | | | 30 | | | | nVs |
| Channel-to-Channel Isolation | CCI | | | -77 | | | | dB |
| AC Feedthrough at I _{OUT1} | F _T | | | -70 | | -65 | | dB |
| Glitch Energy | E _{gl} | | | 160 | | | | nVs |
| Propagation Delay | t _{PD} | | | 220 | | 270 | | ns |
| | | | | | | | | R _L =100Ω, C _L =13pF |
| | | | | | | | | V _{IN} = 6V _{RMS} @ 1 KHz |
| | | | | | | | | Measured for code transition |
| | | | | | | | | Z _S to F _{SS} |
| | | | | | | | | V _{REF} = 10kHz, 20 Vp-p, sinewave |
| | | | | | | | | Z _S to F _S Input Change |
| | | | | | | | | From digital input to 90% |
| | | | | | | | | of final analog output current |

ELECTRICAL CHARACTERISTICS (CONT'D)

| Parameter | Symbol | 25°C | | | Tmin to Tmax | | Units | Test Conditions/Comments |
|--|------------|------|-----|-------|--------------|-------|-------|---|
| | | Min | Typ | Max | Min | Max | | |
| DIGITAL INPUTS³ | | | | | | | | |
| Logical "1" Voltage | V_{IH} | 2.4 | | | 2.4 | | V | |
| Logical "0" Voltage | V_{IL} | | | 0.8 | | 0.8 | V | |
| Input Leakage Current | I_{LKG} | | | ±1 | | ±10 | µA | |
| Input Capacitance ² | | | | | | | | |
| Data | C_{IN} | | | 10 | | 10 | pF | |
| Control | C_{IN} | | | 15 | | 15 | pF | |
| ANALOG OUTPUTS² | | | | | | | | |
| Output Capacitance | | | | | | | | |
| | C_{OUTA} | | | 120 | | 120 | pF | DAC Inputs all 1's |
| | C_{OUTA} | | | 50 | | 50 | pF | DAC Inputs all 0's |
| | C_{OUTB} | | | 120 | | 120 | pF | DAC Inputs all 1's |
| | C_{OUTB} | | | 50 | | 50 | pF | DAC Inputs all 0's |
| POWER SUPPLY⁵ | | | | | | | | |
| Functional Voltage Range ² | V_{DD} | 4.5 | | 15.75 | 4.5 | 15.75 | V | |
| Supply Current | I_{DD} | | | 2 | | 2 | mA | All digital inputs = 0 V or all = 5 V |
| | | | | 2 | | 2 | mA | All digital inputs = V_{IL} or all = V_{IH} |
| SWITCHING CHARACTERISTICS⁴ | | | | | | | | |
| Chip Select to Write Set-Up Time | t_{CS} | 200 | | | 230 | | ns | |
| Chip Select to Write Hold Time | t_{CH} | 20 | | | 30 | | ns | |
| DAC Select to Write Set-Up Time | t_{AS} | 200 | | | 230 | | ns | |
| DAC Select to Write Hold Time | t_{AH} | 20 | | | 30 | | ns | |
| Data Valid to Write Set-Up Time | t_{DS} | 110 | | | 130 | | ns | |
| Data Valid to Write Hold Time | t_{DH} | 0 | | | 0 | | ns | |
| Write Pulse Width | t_{WR} | 180 | | | 200 | | ns | |

NOTES:

- 1 Full Scale Range (FSR) is 10V for unipolar mode.
- 2 Guaranteed but not production tested.
- 3 Digital input levels should not go below ground or exceed the positive supply voltage, otherwise damage may occur.
- 4 See timing diagram.
- 5 Specified values guarantee functionality. Refer to other parameters for accuracy.

Specifications are subject to change without notice

ELECTRICAL CHARACTERISTICS

($V_{DD} = +15\text{ V}$, $V_{REF} = +10\text{ V}$ unless otherwise noted)

| Parameter | Symbol | 25°C | | | Tmin to Tmax | | Units | Test Conditions/Comments |
|---|------------|------|-----|-------|--------------|-----|--------|---|
| | | Min | Typ | Max | Min | Max | | |
| STATIC PERFORMANCE¹ | | | | | | | | |
| Resolution (All Grades) | N | 8 | | | 8 | | | Bits |
| Integral Non-Linearity (Relative Accuracy) | INL | | | | | | LSB | End Point Linearity Spec. |
| J, A, S | | | | ±1 | | | | ±1 |
| K, B, T | | | | ±1/2 | | | | ±1/2 |
| L, C | | | | ±1/4 | | | | ±1/4 |
| Monotonicity | | | | | | | | Guaranteed over temp |
| Differential Non-Linearity | DNL | | | | | | LSB | All grades monotonic over full temperature range. |
| J, A, S | | | | ±1 | | | | ±1 |
| K, B, T | | | | ±1 | | | | ±1 |
| L, C | | | | ±1 | | | | ±1 |
| Gain Error | GE | | | | | | LSB | Using Internal R_{FB} Digital Inputs = V_{INH} |
| J, A, S | | | | ±4 | | | | ±5 |
| K, B, T | | | | ±2 | | | | ±3 |
| L, C | | | | ±1 | | | | ±1 |
| Gain Temperature Coefficient ² | TC_{GE} | | | | | | ±35 | ppm/°C $\Delta\text{Gain}/\Delta\text{Temperature}$ |
| Power Supply Rejection Ratio | PSRR | | | ±100 | | | ±200 | ppm/% $ \Delta\text{Gain}/\Delta V_{DD} \Delta V_{DD} = \pm 5\%$ Digital Inputs = V_{INH} |
| Output Leakage Current (Pin 2) | I_{OUT1} | | | ±50nA | | | ±200nA | nA Digital Inputs = V_{INL} |
| Output Leakage Current (Pin 20) | I_{OUT2} | | | ±50nA | | | ±200nA | nA Digital Inputs = V_{INH} |
| Input Resistance | V_{REFA} | 8 | | 15 | 8 | 15 | kΩ | TC = -300 ppm/°C max. 11 kΩ typical |
| | V_{REFB} | 8 | | 15 | 8 | 15 | kΩ | |
| Input Resistance Matching | | | | ±1 | | | ±1 | % |
| DYNAMIC PERFORMANCE² | | | | | | | | |
| Harmonic Distortion | THD | | -85 | | | | | dB |
| Digital Crosstalk | Q | | 60 | | | | | nVs |
| Channel-to-Channel Isolation | CCI | | -77 | | | | | dB |
| AC Feedthrough at I_{OUT1} | F_T | | -70 | | -65 | | | dB |
| Glitch Energy | Egl | | 440 | | | | | nVs |
| Propagation Delay | t_{PD} | | | 80 | | 100 | | ns |
| $R_L=100\Omega$, $C_L=13\text{pF}$ $V_{IN} = 6V_{RMS}$ @ 1 KHz Measured for code transition ZS to F_S $V_{REF} = 10\text{kHz}$, 20 Vp-p, sinewave ZS to F_S Input Change From 50% of digital input to 90% of final analog output current | | | | | | | | |
| DIGITAL INPUTS³ | | | | | | | | |
| Logical "1" Voltage | V_{IH} | 13.5 | | | 13.5 | | | V |
| Logical "0" Voltage | V_{IL} | | | 1.5 | | 1.5 | | V |
| Input Leakage Current | I_{ILKG} | | | ±1 | | ±10 | | μA |
| Input Capacitance ² | | | | | | | | |
| Data | C_{IN} | | | 10 | | 10 | | pF |
| Control | C_{IN} | | | 15 | | 15 | | pF |

ELECTRICAL CHARACTERISTICS (CONT'D)

| Parameter | Symbol | 25°C | | | Tmin to Tmax | | Units | Test Conditions/Comments |
|---------------------------------------|-------------------|------|-----|-------|--------------|-------|-------|---|
| | | Min | Typ | Max | Min | Max | | |
| ANALOG OUTPUTS² | | | | | | | | |
| Output Capacitance | | | | | | | | |
| | C _{OUTA} | | | 120 | | 120 | pF | DAC Inputs all 1's |
| | C _{OUTA} | | | 50 | | 50 | pF | DAC Inputs all 0's |
| | C _{OUTB} | | | 120 | | 120 | pF | DAC Inputs all 1's |
| | C _{OUTB} | | | 50 | | 50 | pF | DAC Inputs all 0's |
| POWER SUPPLY⁵ | | | | | | | | |
| Functional Voltage Range ² | V _{DD} | 4.5 | | 15.75 | 4.5 | 15.75 | V | |
| Supply Current | I _{DD} | | | 2 | | 2 | mA | All digital inputs = 0 V or all = 5 V |
| | | | | 2 | | 2 | mA | All digital inputs = V _{IL} or all = V _{IH} |
| SWITCHING CHARACTERISTICS | | | | | | | | |
| Chip Select to Write Set-Up Time | t _{CS} | 60 | | | 80 | | ns | |
| Chip Select to Write Hold Time | t _{CH} | 10 | | | 15 | | ns | |
| DAC Select to Write Set-Up Time | t _{AS} | 60 | | | 80 | | ns | |
| DAC Select to Write Hold Time | t _{AH} | 10 | | | 15 | | ns | |
| Data Valid to Write Set-Up Time | t _{DS} | 30 | | | 40 | | ns | |
| Data Valid to Write Hold Time | t _{DH} | 0 | | | 0 | | ns | |
| Write Pulse Width | t _{WR} | 60 | | | 80 | | ns | |

NOTES:

- 1 Full Scale Range (FSR) is 10V for unipolar mode.
- 2 Guaranteed but not production tested.
- 3 Digital input levels should not go below ground or exceed the positive supply voltage, otherwise damage may occur.
- 4 See timing diagram.
- 5 Specified values guarantee functionality. Refer to other parameters for accuracy.

Specifications are subject to change without notice

ABSOLUTE MAXIMUM RATINGS (TA = +25°C unless otherwise noted)^{1, 2, 3}

| | | | |
|---|---------------|--|-----------------|
| V _{DD} to GND | +17 V | V _{RFBA} , V _{RFBB} to GND | ±25 V |
| AGND to DGND | ±1 V | Storage Temperature | -65°C to +150°C |
| (Functionality Guaranteed ±0.5 V) | | Lead Temperature (Soldering, 10 secs.) | +300°C |
| Digital Input Voltage to DGND | -0.5 V, +17 V | Package Power Dissipation Rating to 75°C | |
| V _{PIN2} , V _{PIN20} to GND | -0.5 V, +17 V | CDIP, PDIP, SOIC, PLCC | 900mW |
| V _{REFA} , V _{REFB} to GND | ±25 | Derates above 75°C | 12mW/°C |

NOTES:

- 1 Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation at or above this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability.
- 2 Any input pin which can see a value outside the absolute maximum ratings should be protected by Schottky diode clamps (HP5082-2835) from input pin to the supplies.
- 3 GND refers to AGND and DGND.

INTERFACE LOGIC INFORMATION

DAC Selection: Both DAC latches share a common 8-bit input port. The control input $\overline{\text{DAC A/DAC B}}$ selects which DAC can accept data from the input port.

Mode Selection: Inputs $\overline{\text{CS}}$ and $\overline{\text{WR}}$ control the operating mode of the selected DAC. See Mode Selection Table below:

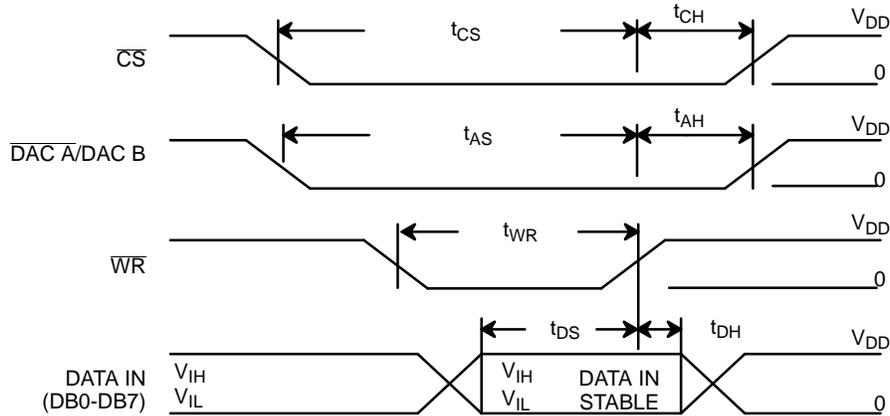
Write Mode: When $\overline{\text{CS}}$ and $\overline{\text{WR}}$ are both low the selected DAC is in the write mode. The input data latches of the selected DAC are transparent and its analog output responds to activity on DB0-DB7.

Hold Mode: The selected DAC latch retains the data which was present on DB0-DB7 just prior to $\overline{\text{CS}}$ and $\overline{\text{WR}}$ assuming a high state. Both analog outputs remain at the values corresponding to the data in their respective latches.

| DAC A/DAC B | $\overline{\text{CS}}$ | $\overline{\text{WR}}$ | DAC A | DAC B |
|-------------|------------------------|------------------------|-------|-------|
| L | L | L | Write | Hold |
| H | L | L | Hold | Write |
| X | H | X | Hold | Hold |
| X | X | H | Hold | Hold |

L = LOW state, H = HIGH state, X = Don't care state

Table 1. Mode Selection Table

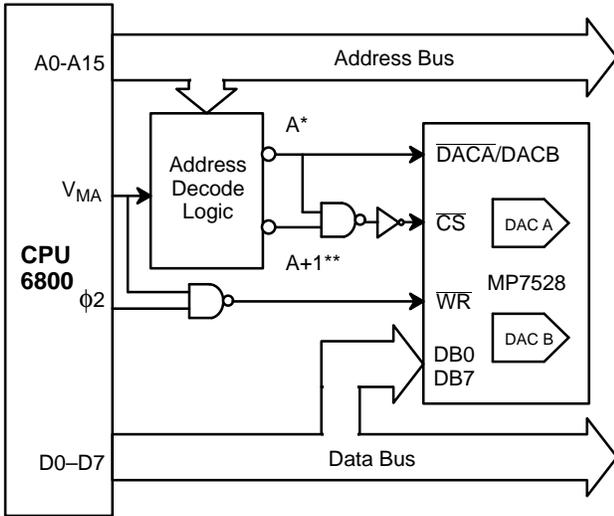


NOTES:

- All input signal rise and fall times measured from 10% to 90% of V_{DD} .
 $V_{DD} = +5\text{ V}$, $t_r = t_f = 20\text{ ns}$
 $V_{DD} = +15\text{ V}$, $t_r = t_f = 40\text{ ns}$
- Timing measurement reference level is $V_{IH} + V_{IL} / 2$

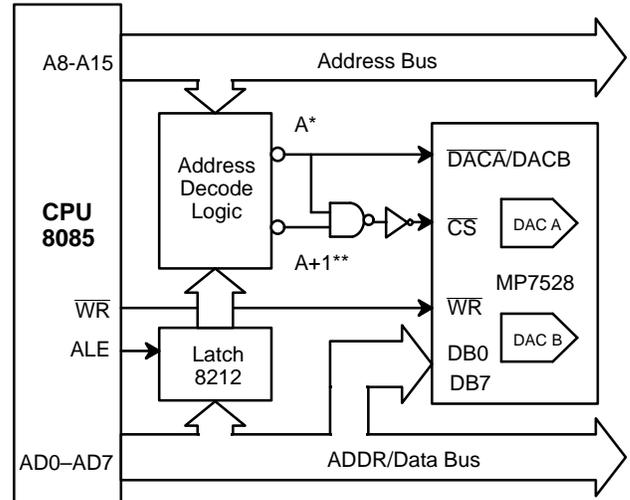
Figure 1. Write Cycle Timing Diagram

MICROPROCESSOR INTERFACE



Analog circuitry has been omitted for clarity
 *A = Decoded 7528 DAC A Address
 **A + 1 = Decoded 7528 DAC B Address

Figure 2. MP7528 Dual DAC to 6800 CPU Interface



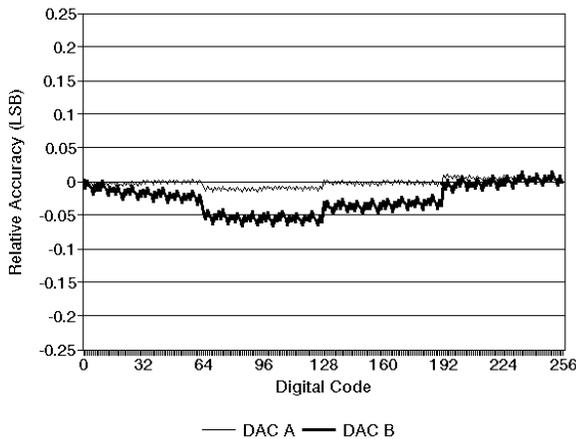
Analog circuitry has been omitted for clarity
 *A = Decoded 7528 DAC A Address
 **A + 1 = Decoded 7528 DAC B Address

NOTE:

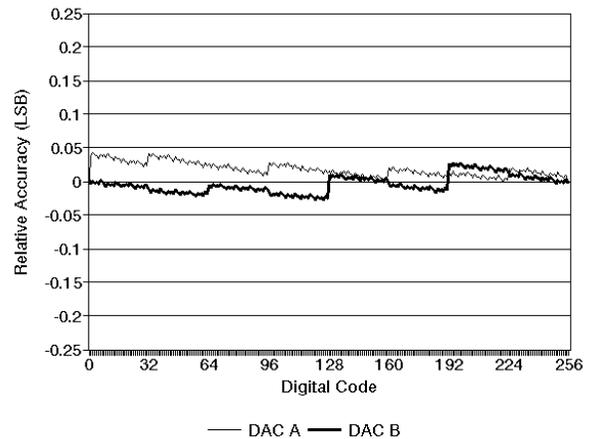
8085 instruction SHLD (store H & L direct) can update both DACS with data from H and L registers

Figure 3. MP7528 Dual DAC to 8085 CPU Interface

PERFORMANCE CHARACTERISTICS



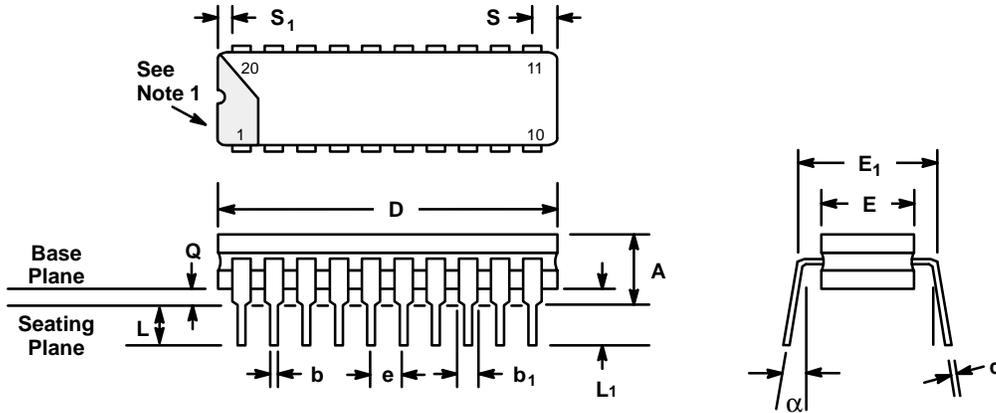
Graph 1. Relative Accuracy vs. Digital Code 5 V



Graph 2. Relative Accuracy vs. Digital Code 15 V

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**20 LEAD CERAMIC DUAL-IN-LINE
(300 MIL CDIP)
D20**

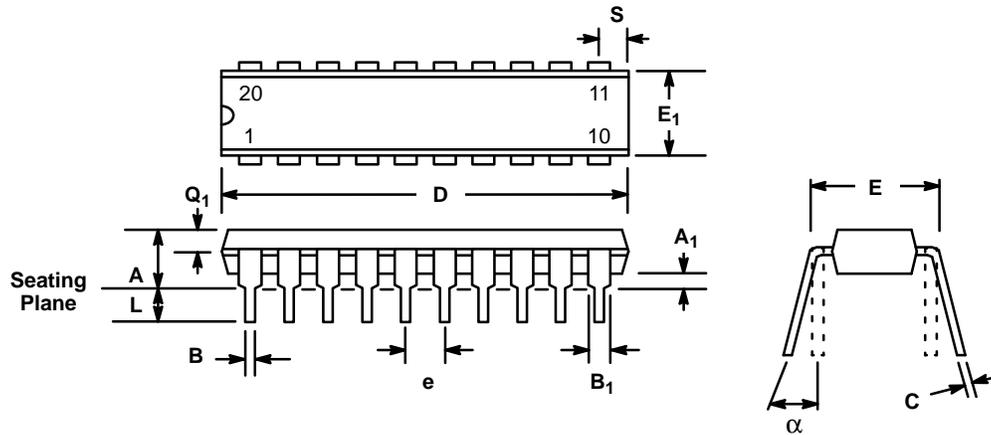


| SYMBOL | INCHES | | MILLIMETERS | | NOTES |
|----------------|-----------|-------|-------------|-------|-------|
| | MIN | MAX | MIN | MAX | |
| A | — | 0.200 | — | 5.08 | — |
| b | 0.014 | 0.023 | 0.356 | 0.584 | — |
| b ₁ | 0.038 | 0.065 | 0.965 | 1.65 | 2 |
| c | 0.008 | 0.015 | 0.203 | 0.381 | — |
| D | — | 1.060 | — | 26.92 | 4 |
| E | 0.220 | 0.310 | 5.59 | 7.87 | 4 |
| E ₁ | 0.290 | 0.320 | 7.37 | 8.13 | 7 |
| e | 0.100 BSC | | 2.54 BSC | | 5 |
| L | 0.125 | 0.200 | 3.18 | 5.08 | — |
| L ₁ | 0.150 | — | 3.81 | — | — |
| Q | 0.015 | 0.070 | 0.381 | 1.78 | 3 |
| S | — | 0.080 | — | 2.03 | 6 |
| S ₁ | 0.005 | — | 0.13 | — | 6 |
| α | 0° | 15° | 0° | 15° | — |

NOTES

1. Index area; a notch or a lead one identification mark is located adjacent to lead one and is within the shaded area shown.
2. The minimum limit for dimension b₁ may be 0.023 (0.58 mm) for all four corner leads only.
3. Dimension Q shall be measured from the seating plane to the base plane.
4. This dimension allows for off-center lid, meniscus and glass overrun.
5. The basic lead spacing is 0.100 inch (2.54 mm) between centerlines.
6. Applies to all four corners.
7. This is measured to outside of lead, not center.

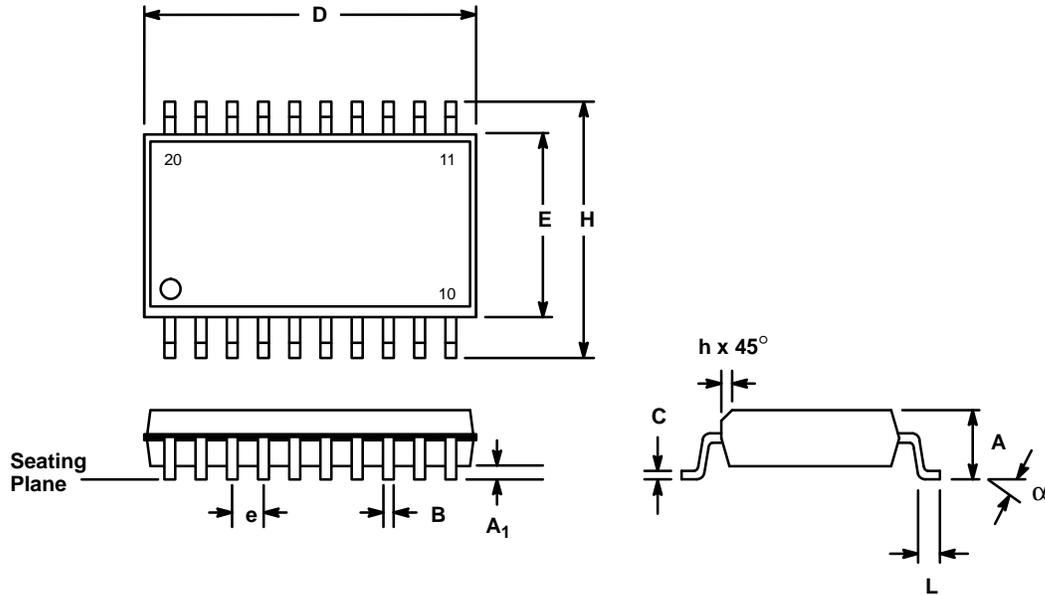
20 LEAD PLASTIC DUAL-IN-LINE (300 MIL PDIP) N20



| SYMBOL | INCHES | | MILLIMETERS | |
|--------------------|-----------|-------|-------------|-------|
| | MIN | MAX | MIN | MAX |
| A | — | 0.200 | — | 5.08 |
| A ₁ | 0.015 | — | 0.38 | — |
| B | 0.014 | 0.023 | 0.356 | 0.584 |
| B ₁ (1) | 0.038 | 0.065 | 0.965 | 1.65 |
| C | 0.008 | 0.015 | 0.203 | 0.381 |
| D | 0.945 | 1.060 | 24.0 | 26.92 |
| E | 0.295 | 0.325 | 7.49 | 8.26 |
| E ₁ | 0.220 | 0.310 | 5.59 | 7.87 |
| e | 0.100 BSC | | 2.54 BSC | |
| L | 0.115 | 0.150 | 2.92 | 3.81 |
| α | 0° | 15° | 0° | 15° |
| Q ₁ | 0.055 | 0.070 | 1.40 | 1.78 |
| S | 0.040 | 0.080 | 1.02 | 2.03 |

Note: (1) The minimum limit for dimensions B₁ may be 0.023" (0.58 mm) for all four corner leads only.

**20 LEAD SMALL OUTLINE
(300 MIL JEDEC SOIC)
S20**



| SYMBOL | INCHES | | MILLIMETERS | |
|----------------|-----------|--------|-------------|-------|
| | MIN | MAX | MIN | MAX |
| A | 0.097 | 0.104 | 2.464 | 2.642 |
| A ₁ | 0.0050 | 0.0115 | 0.127 | 0.292 |
| B | 0.014 | 0.019 | 0.356 | 0.483 |
| C | 0.0091 | 0.0125 | 0.231 | 0.318 |
| D | 0.500 | 0.510 | 12.70 | 12.95 |
| E | 0.292 | 0.299 | 7.42 | 7.59 |
| e | 0.050 BSC | | 1.27 BSC | |
| H | 0.400 | 0.410 | 10.16 | 10.41 |
| h | 0.010 | 0.016 | 0.254 | 0.406 |
| L | 0.016 | 0.035 | 0.406 | 0.889 |
| α | 0° | 8° | 0° | 8° |

Notes

Notes

NOTICE

EXAR Corporation reserves the right to make changes to the products contained in this publication in order to improve design, performance or reliability. EXAR Corporation assumes no responsibility for the use of any circuits described herein, conveys no license under any patent or other right, and makes no representation that the circuits are free of patent infringement. Charts and schedules contains here in are only for illustration purposes and may vary depending upon a user's specific application. While the information in this publication has been carefully checked; no responsibility, however, is assumed for inaccuracies.

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